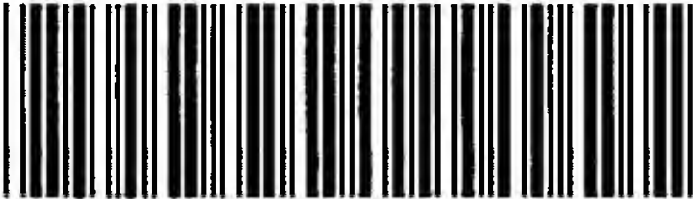


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,890	LIN ET AL.	
	Examiner	Art Unit	
	Wen-Ying P. Chen	2871	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Key word search in US-PGPUB,USPAT,USOCR,EPO,JPO,D ERWENT,IBM_TDB databases in EAST: see search history printout	9/22/2005	WPC WPL